



Interrogating vacuum arc physics with advanced diagnostic methods

Presentation to:

**3rd International Workshop on Mechanisms of Vacuum Arcs
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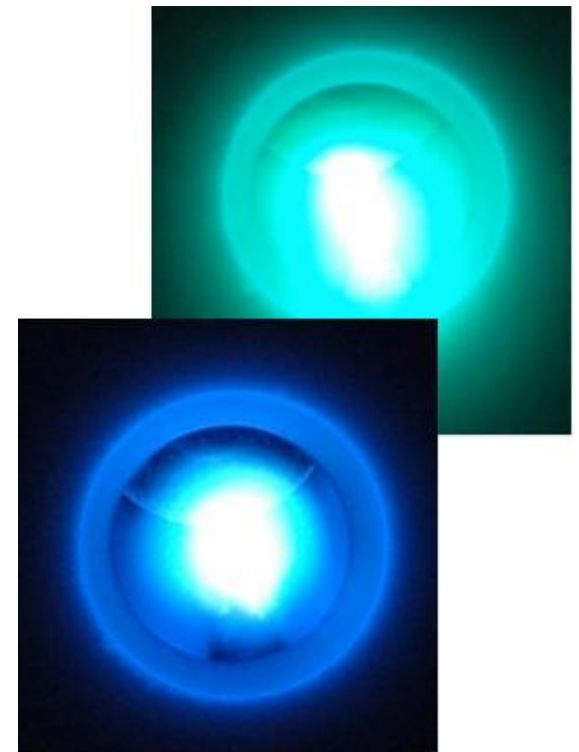
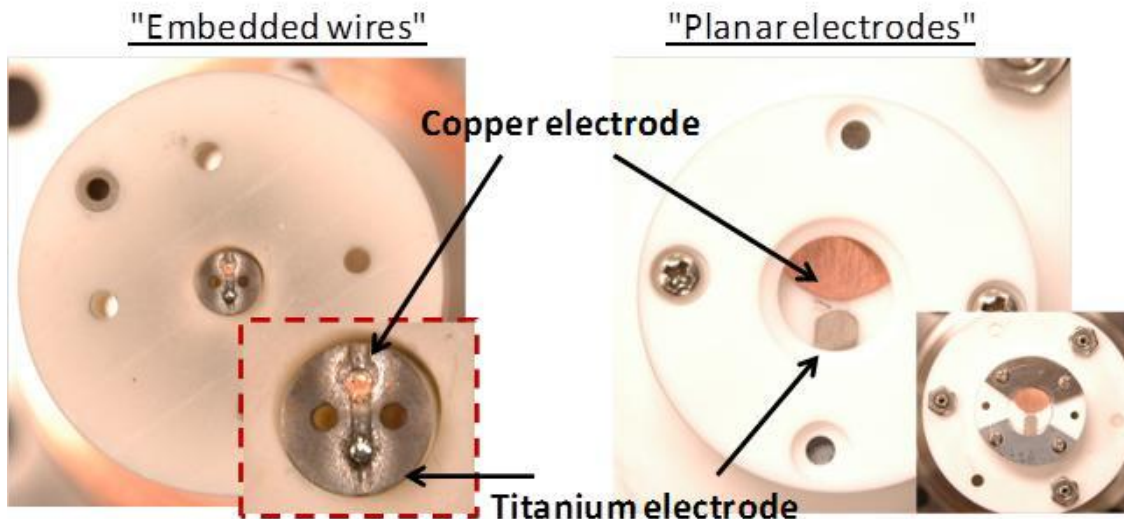
Vacuum arcs represent challenging environments both computationally and experimentally

- For us, the arc is a “good thing”
 - We use it to generate high density plasma
- Our main challenge is to have a reliable, reproducible arc
 - Do the same thing over and over
- Central questions include
 - What is present in the arc?
 - When is it generated?
 - Where is it generated from?
 - What are these species properties?
 - How does the output change with operation
- Answers to these questions help us understand
 - Phenomena of arc generation and maintenance
 - Plasma transport from the source

Our progression has been from “far” to the “near”

Introduction to the types of arcs we are considering

- Experiments need to be flexible and versatile
 - Test predictive capabilities of code
 - Target desired physics
 - Overcome intrinsic headaches associated with arcs
- Co-planar two electrode metal arcs embedded in ceramic sleeves
 - Various configurations and compositions
 - Mostly vacuum, but not always

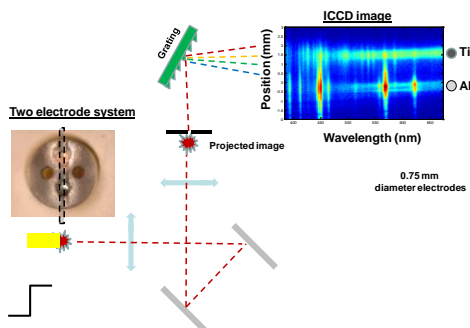


A wide range of diagnostic techniques are needed to study arc physics

- A wide range of techniques can be utilized to probe aspects of plasma generated in an arc
 - Our challenge is to match the right tool to the right job
- Tools can consist of
 - "Global" current and voltage
 - Semi-localized optical emission and ion beam spectroscopies
 - Localized laser induced fluorescence, absorption and or scattering

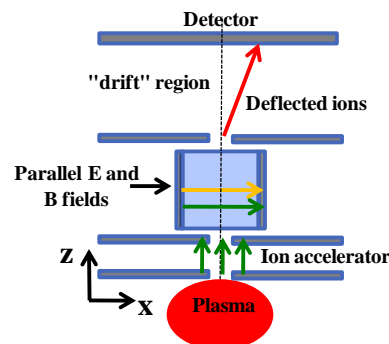
Optical diagnostics

“Near the source”



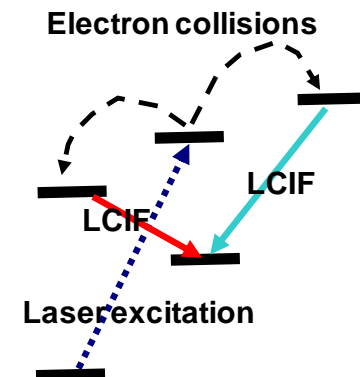
Ion-based diagnostics

“Downstream”



Laser spectroscopy

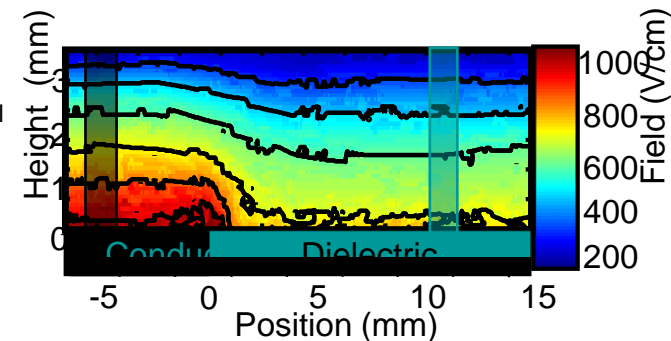
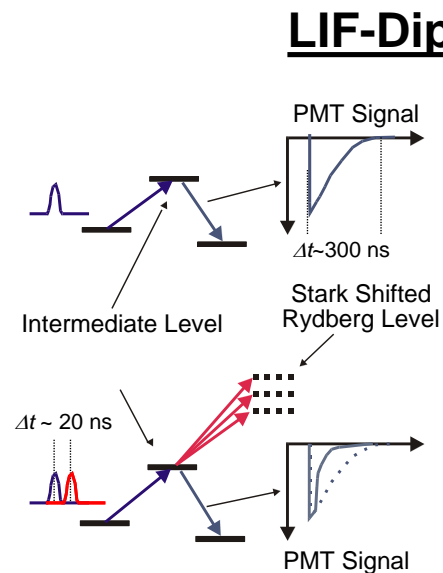
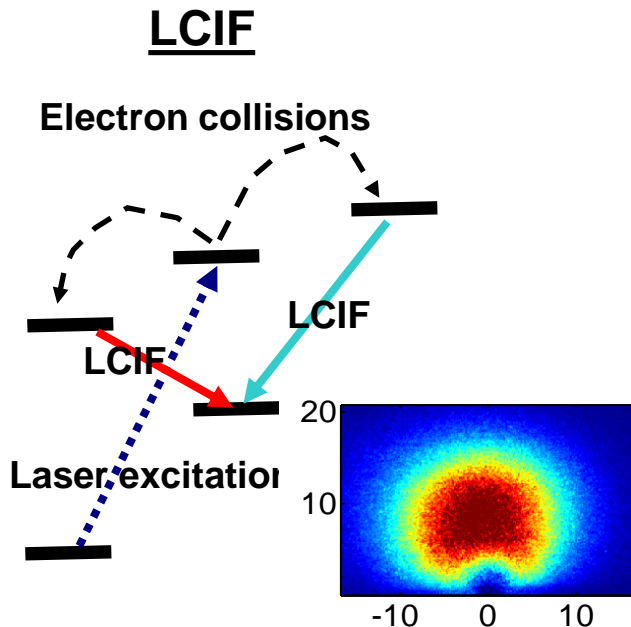
“Bridge the gap”



Emphasis is placed on laser based diagnostics

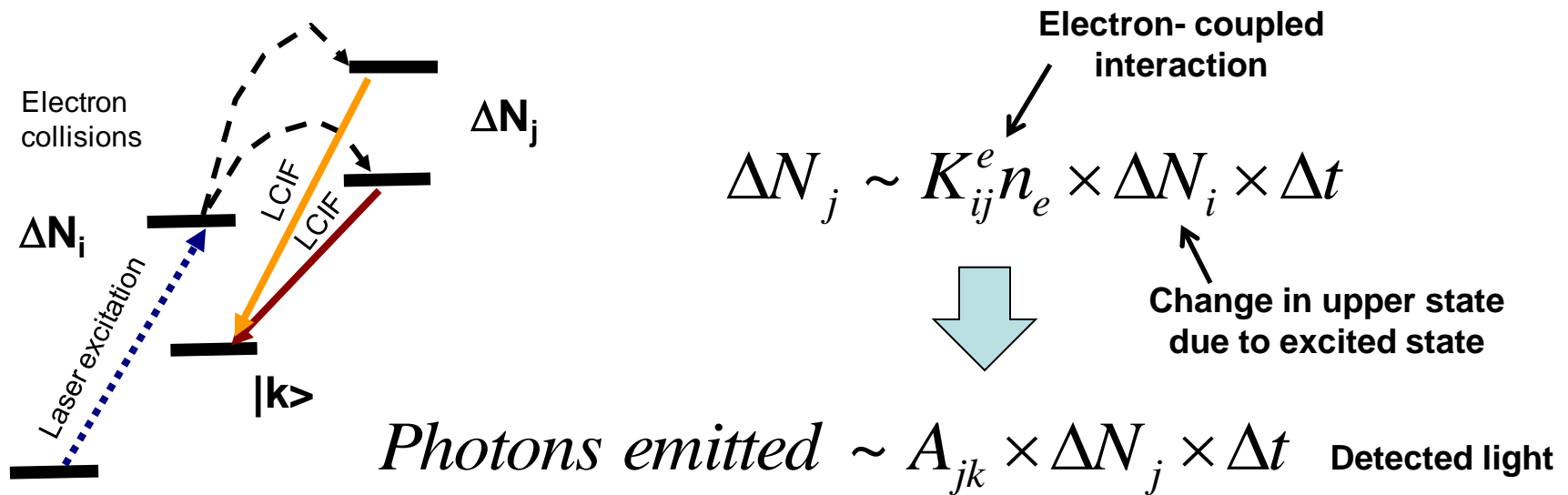
Laser based diagnostics facilitate measurements of the arc environment

- Laser diagnostics offer good spatial and temporal resolution
 - Region of interrogation limited to where the beam is
 - Temporal resolution governed atomic response
- “Minor” perturbations to the plasma
 - Some redistribution of excited states, possibly some ionization
- Diagnostics based on laser-induced fluorescence (LIF)
 - Laser collision induced fluorescence (LCIF) for electron densities
 - LIF-Dip for electric fields



LCIF is based on redistribution of excited state by plasma electrons

- Laser excitation populates an intermediate state
 - Relaxation processes deplete the excited state
- Portion of excited state population gets redistributed into "uphill" states
 - Driven by interaction with energetic plasma species (electrons)



LCIF looks for changes in emission of neighboring "uphill" states after laser excitation

Redistribution after laser excitation is complex

- A "good" model is required to predict transfer between levels
 - Employ a collisional-radiative model (CRM) to predict redistribution

$$\frac{dN_j}{dt} = \underbrace{\left[\sum_{i \neq j} K_{ij}^e N_i - \sum_{i \neq j} K_{ji}^e N_j \right]}_{\text{"Electron mixing"}} n_e + \underbrace{\left[\sum_{i > j} A_{ij} N_i - \sum_{i < j} A_{ji}^j N_j \right]}_{\text{"Photon mixing"}} + \sum_k \underbrace{\left[\sum_{i \neq j} K_{ikj}^a N_i - \sum_{i \neq j} K_{jki}^a N_j \right]}_{\text{"Neutral mixing"}} N_k$$

- Electron density and electron temperature appear in first term
 - Temperature dependence introduced via K_{ij}^e

Electron-temperature dependent rates

$$K_{ij}^e = \langle \sigma_{ij}(E) v_e \rangle$$

Distribution function used for describing electron velocities

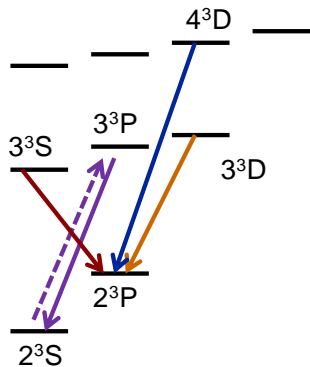
$$f(v) \sim e^{-\frac{(1/2)mv^2}{kT}}$$

Approach is applicable to various atomic and molecular systems of interest

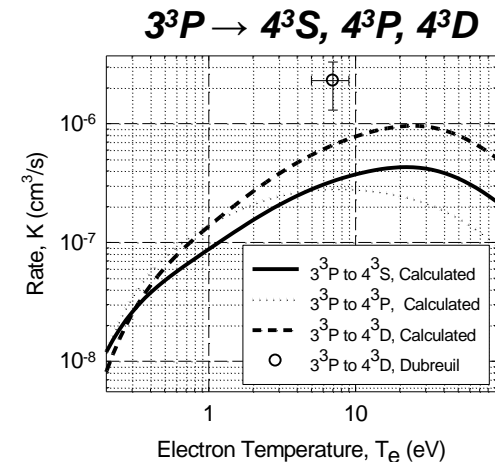
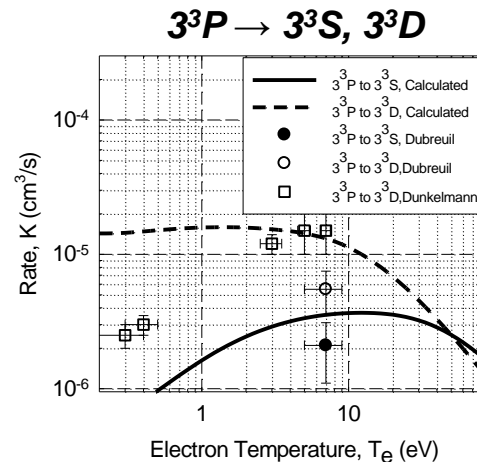
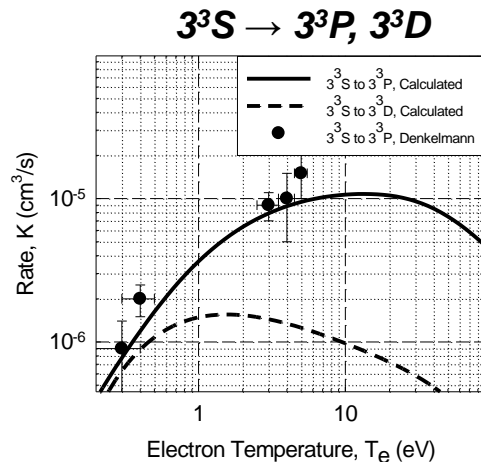
Helium atom serves as target species for LCIF measurements

- Employ Helium to start with - considering argon
 - "Simple system" with "better known" rates
- Utilize functionalized form of cross-sections compiled by Ralchenko¹
 - Integrate to get rates, compare to measured rates^{2,3}

Key transitions



Computed and measured excitation rates in Helium



- 1: Yu. Ralchenko, R. K. Janev, T. Kato, D. V. Fursa, I. Bray, F. J. De Heer, Atomic Data and Nuclear Data Tables 94, 603 (2008)
- 2: R. Denkermann, S. Maurmann, T. Lokajczyk, P. Drepper, and H. -J. Kunze, J. Phys. B: At. Mol. Opt. Phys. 32, 4635 (1999).
R. Denkermann, S. Freund and S. Maurmann, Contrib. Plasma Phys. 40, 91 (2000).
- 3: B. Dubreuil and P. Prigent, J. Phys. B: At. Mol. Opt. Phys. 18, 4597 (1985).

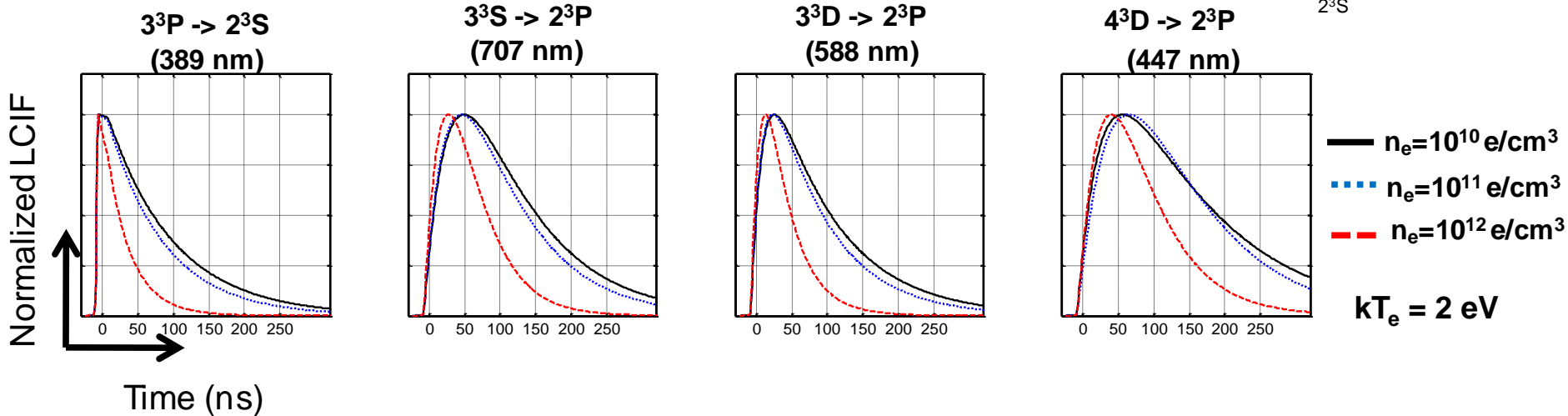
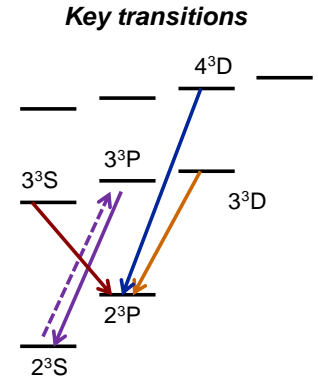
Accuracy of n_e, T_e depend on knowledge of $K_{ij}(kT_e)$

CRM predicts evolution of various helium states after laser excitation

- Temporal evolution serves as a partial "fingerprint" of electron interaction
 - Analyze shape of decay above $n_e \sim 10^{11}$ electrons/cm³
 - Below $n_e \sim 10^{11}$ absolute intensities are needed

$$K_{ij}^e n_e \sim A_{ij} \quad \Rightarrow \quad 10^{-5} \times 10^{11} \sim 10^7$$

Computed temporal evolution

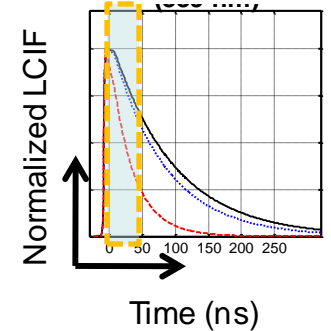


Need at least two time-resolved profiles to uniquely obtain n_e , kT_e

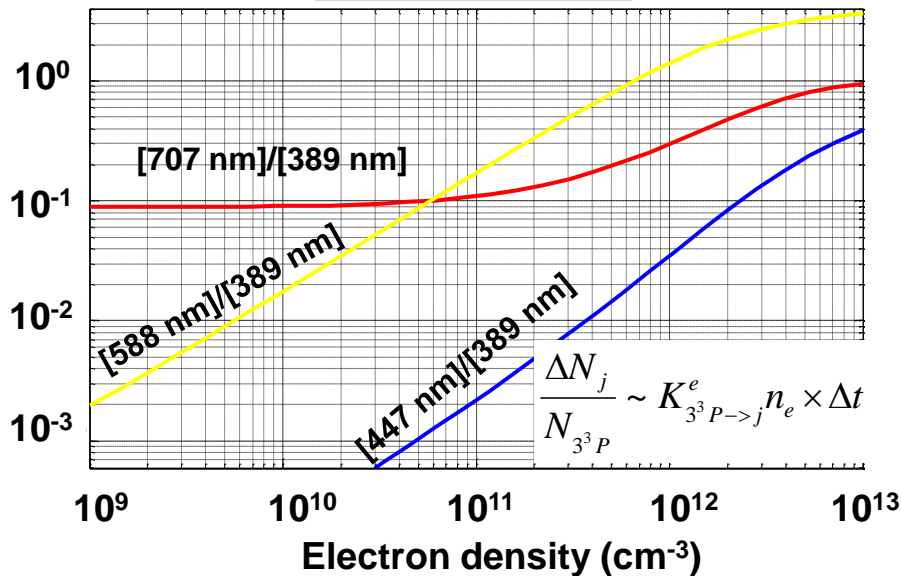
Trends can be extracted to bypass the need for resolving LCIF evolution

- Examine ratios of time integrated LCIF
 - Eliminates need for absolute calibrations
 - Still need relative efficiencies of imaging system
- Capitalize on "kT_e independent" coupling of 3³P to 3³D
 - Ratio of 588 nm to 389 nm yields n_e
 - Density + Ratio of 447nm to 588 nm yields kT_e

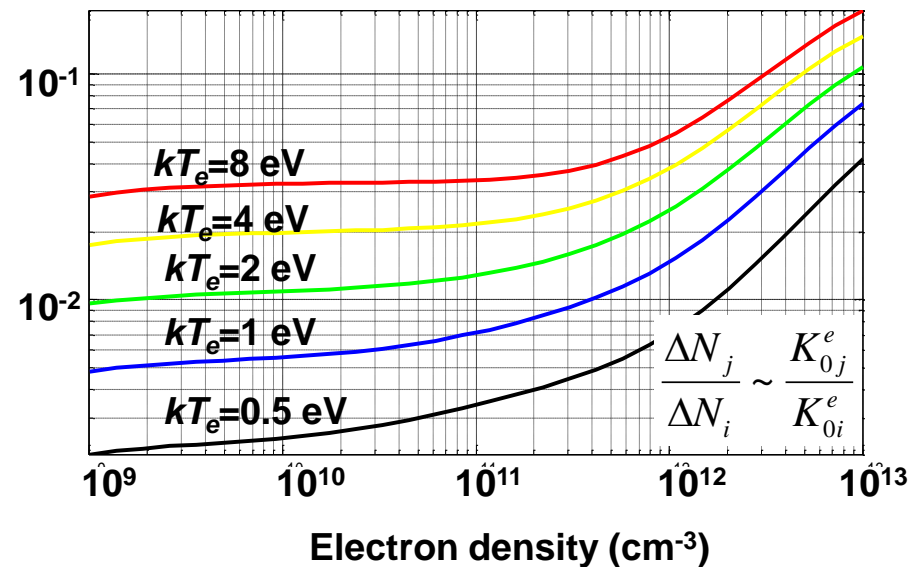
Window of integration



Ratio to 389 nm



Ratio [447 nm]/[588 nm]

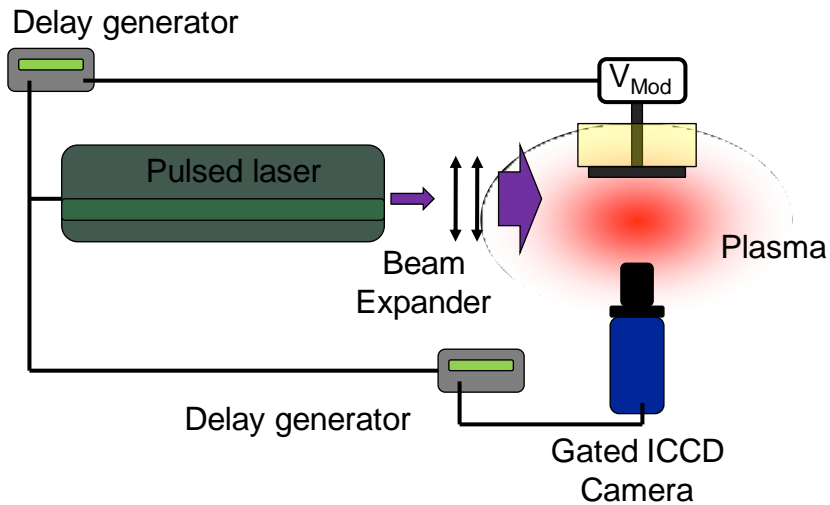


Only need to make three measurements to obtain n_e, kT_e

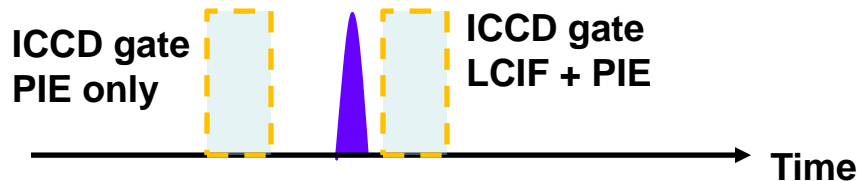
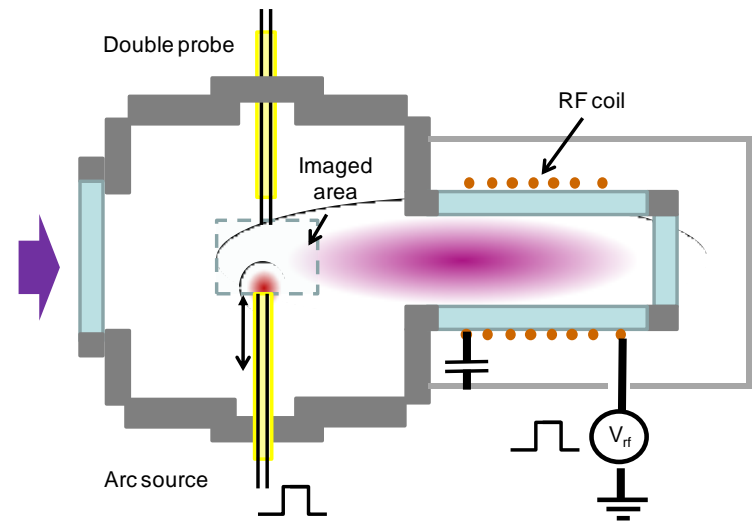
Experimental implementation of the LCIF technique is realized

- Desirable to develop technique over broad range of densities (and temperatures)
 - Expanding arc in helium afterglow
 - Arc moves on translatable stage
 - Double probe to measure ion/electron densities

Optical setup



Vacuum system



Now need six measurements (3x2) n_e , kT_e

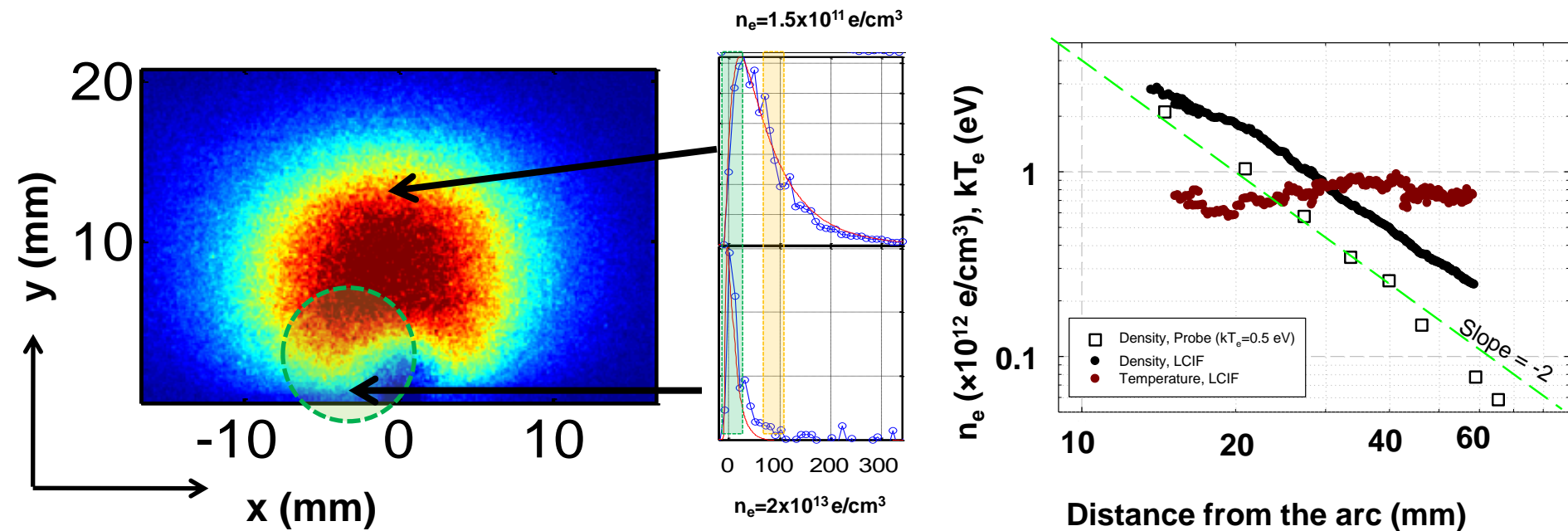
LCIF works quite well over broad density range

- Technique can measure densities from $<10^8$ to $>10^{12}$ e/cm³
 - Demonstrates good spatial resolution (< 1 mm)

Measured profile

Temporal signature

Comparison to double probe

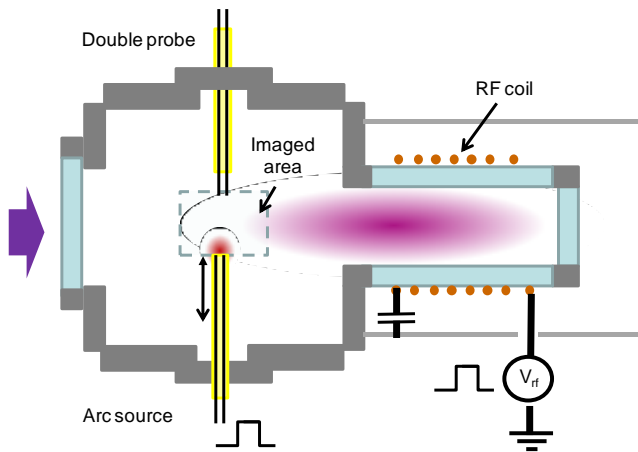


Higher densities ($>10^{13}$) can be measured but time resolution is needed

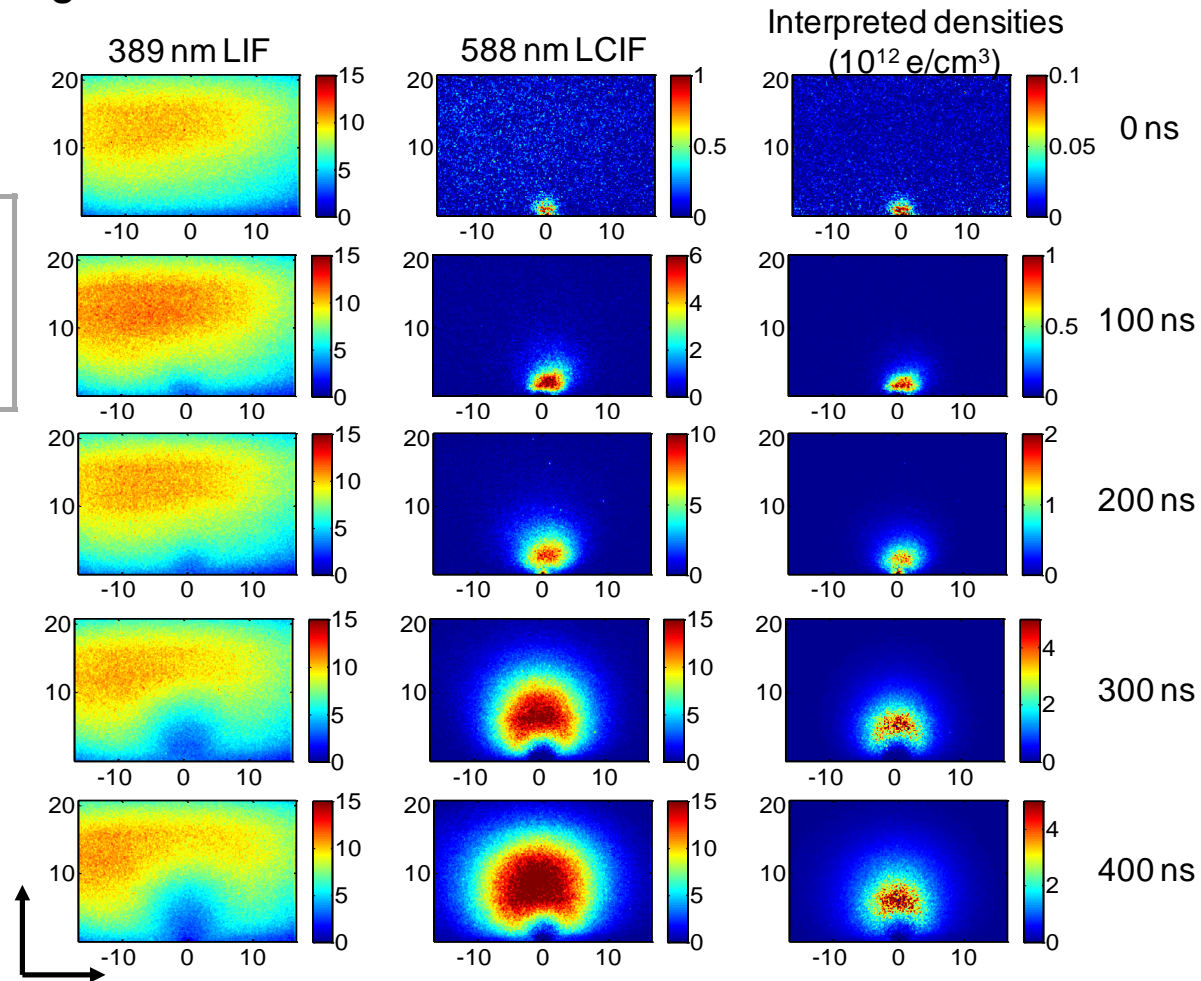
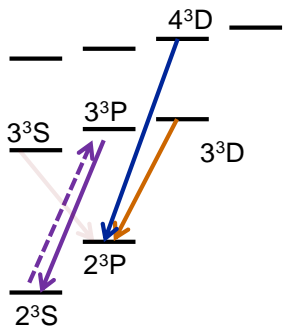
LCIF captures transient phenomenon

Examine generation of arc

- Low pressure (30 mTorr) helium after glow
- Time steps of 100 ns, 50 ns gates

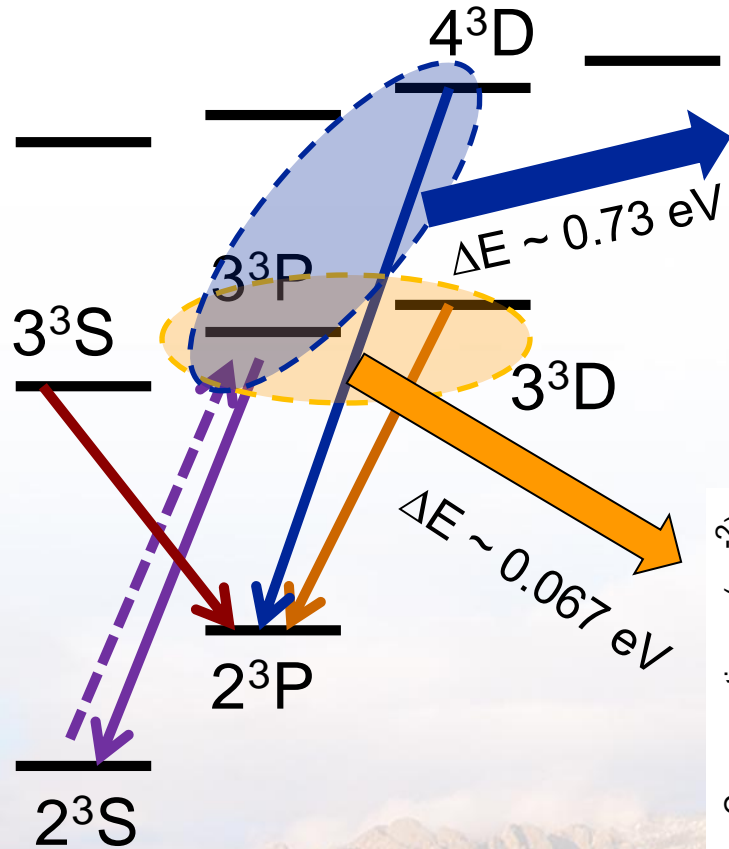


Key transitions

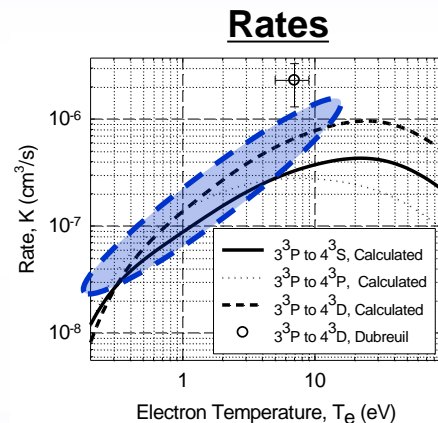
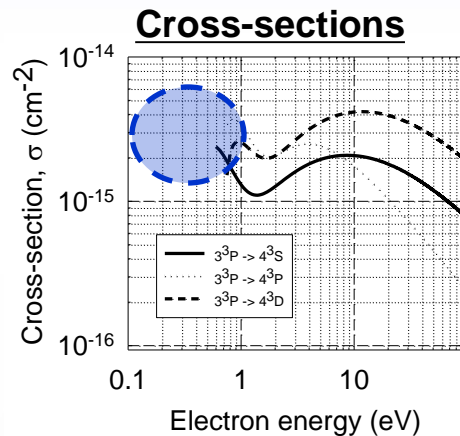


Spatial-temporal maps of arc expansion are illustrated with LCIF

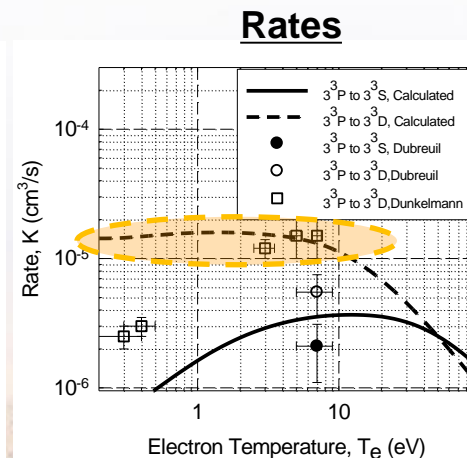
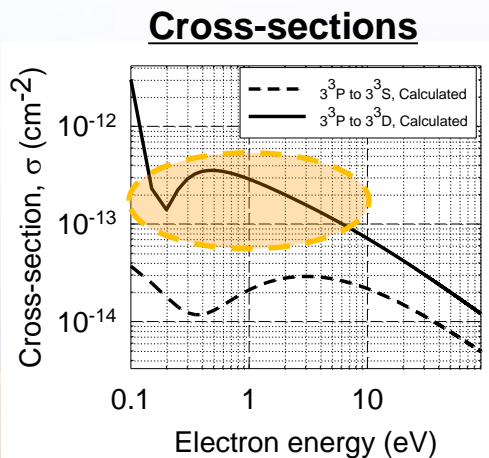
Monitoring higher levels gives measure of "electron temperature"



$3^3P \rightarrow 4^3D$



$3^3P \rightarrow 3^3D$

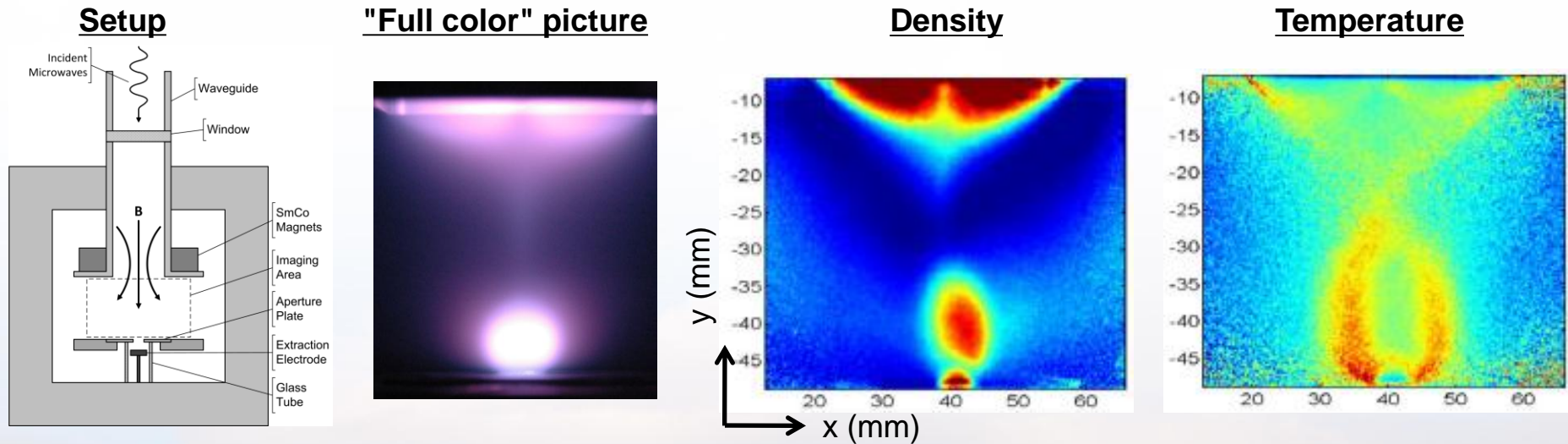


This is a work in progress and quite sensitive to functional forms of rates



“Temperature” measurements have been illustrated in other plasma systems

- Electron temperature concept has been employed in other plasma systems
 - ECR generated plasma cathode experiments
 - NASA driven research interested in electron sources for ion propulsion neutralization

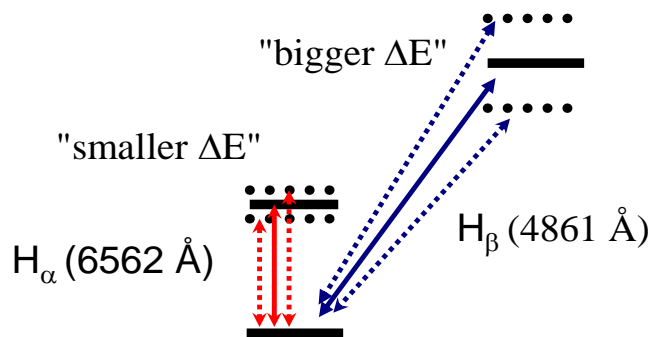


Regions of adjacent plasmas are mediated by electric fields that induce higher electron temperatures

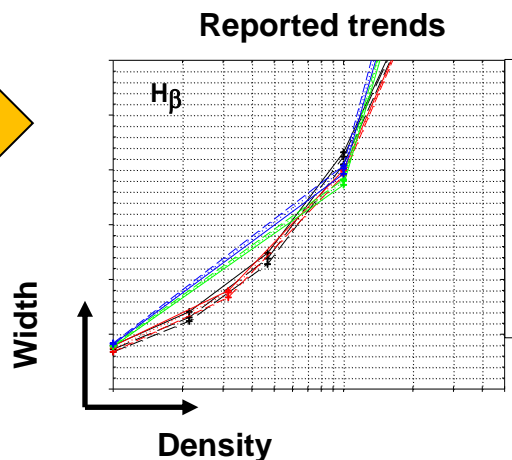
Stark broadening is used to target higher densities

- Electrons and ions "perturb" atomic orbitals
 - Degree of interaction $\sim n_e$ and T_e
- Measured profiles are convolution
 - Stark, Van der Waals, Doppler and Instrument
- Fit profiles to obtain n_e ,

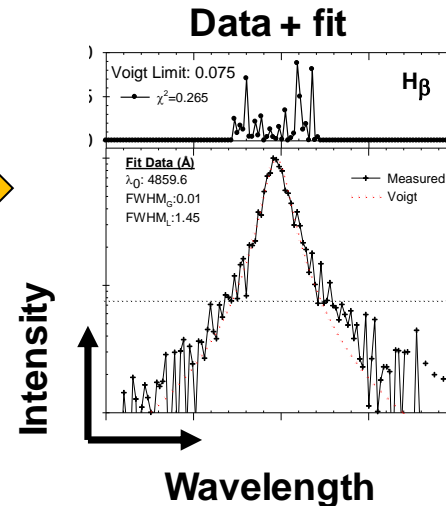
Concept



Scaling trends



Representative results

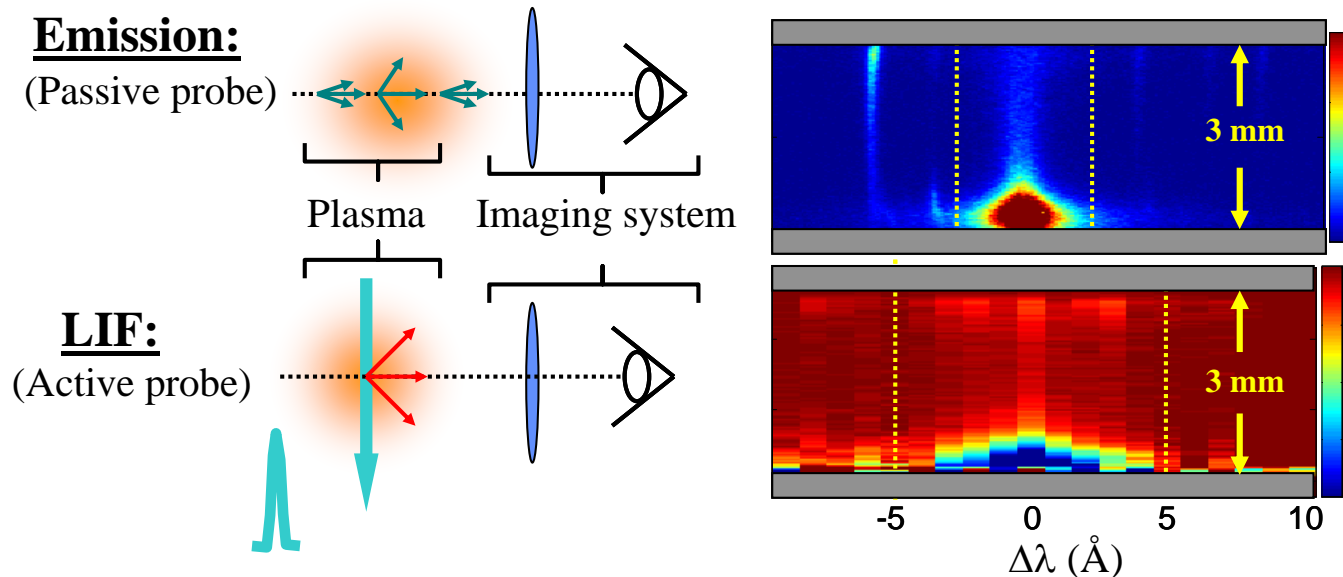


Hydrogen emission is typically used but other species exhibit Stark broadening

Both passive and active interrogation are being considered

- Nanosecond pulsed laser excitation is more difficult, but.....
 - Overcomes "line of sight" convolution
 - Better spectral resolution ($\sim \text{pm}$) than spectrometers ($\sim 10 \text{ pm}$)
 - Can provide 2d spatial maps

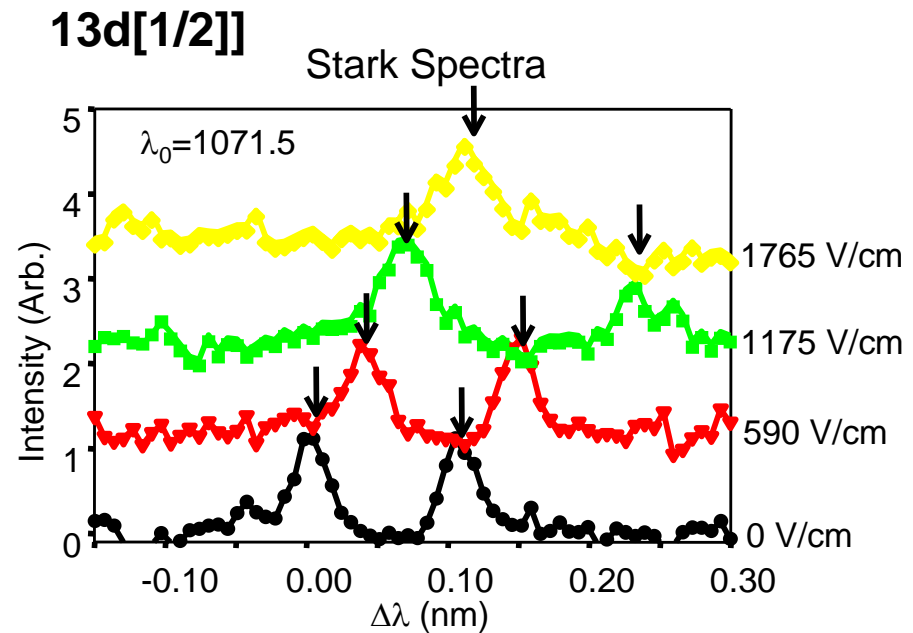
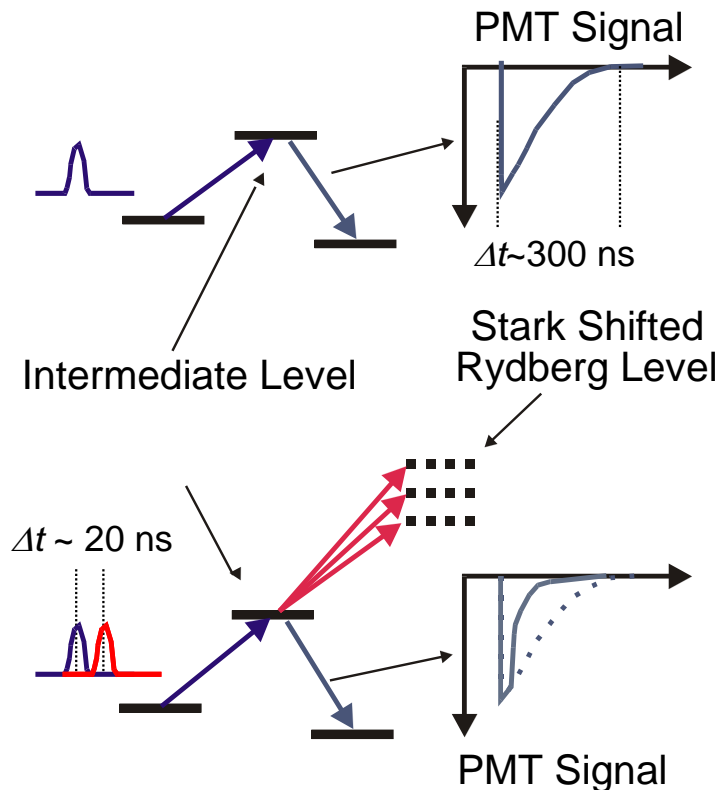
Comparison of the two techniques



Active interrogation provides more accurate measure of line broadening and is free of spectral contamination

LIF-dip technique detects Stark-shifted states of probed atoms

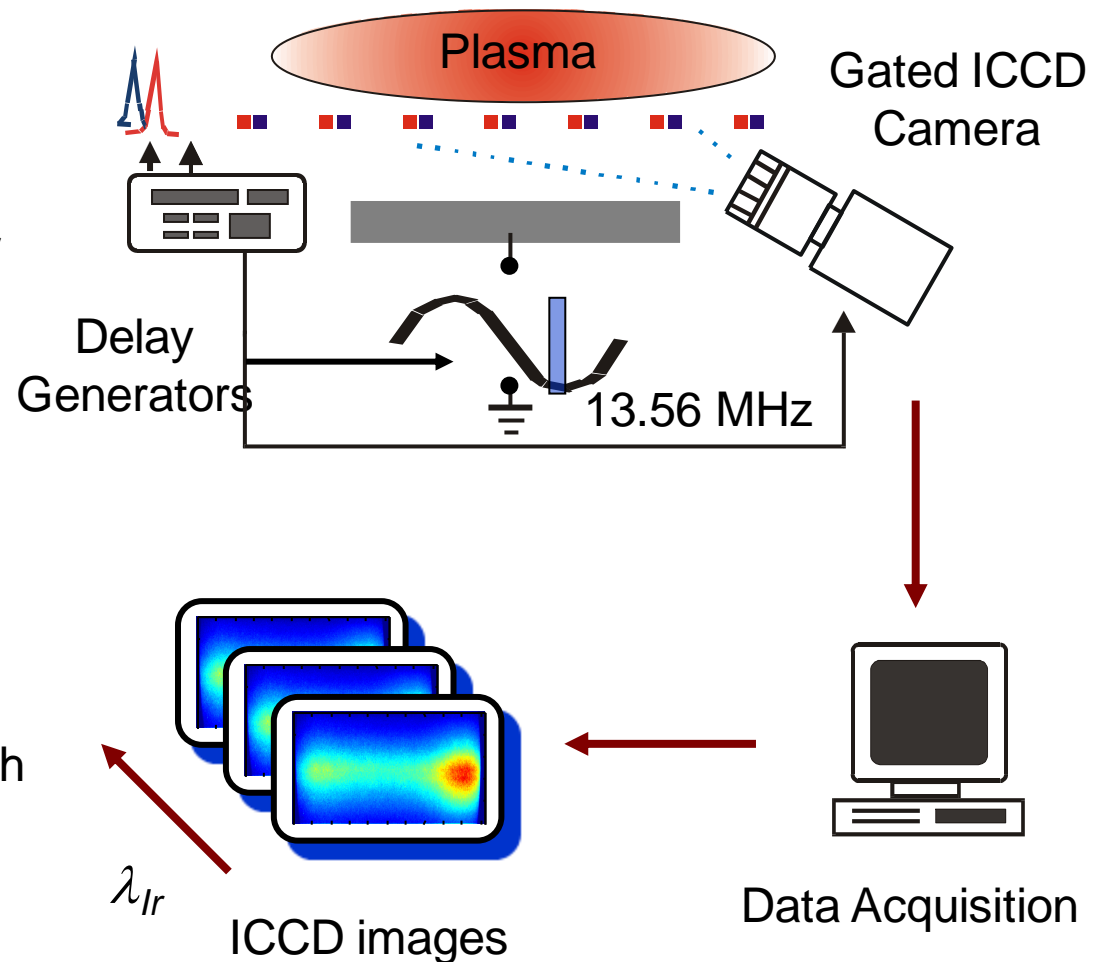
- Fluorescence dip spectroscopy is a two laser technique
 - Probe Stark-shifted Rydberg states
- Transition to the Rydberg level is monitored by a “dip” in the fluorescence from the intermediate state



Electric field sensitivity is determined by Rydberg level probed

Typical 2D LCIF-dip experimental arrangement

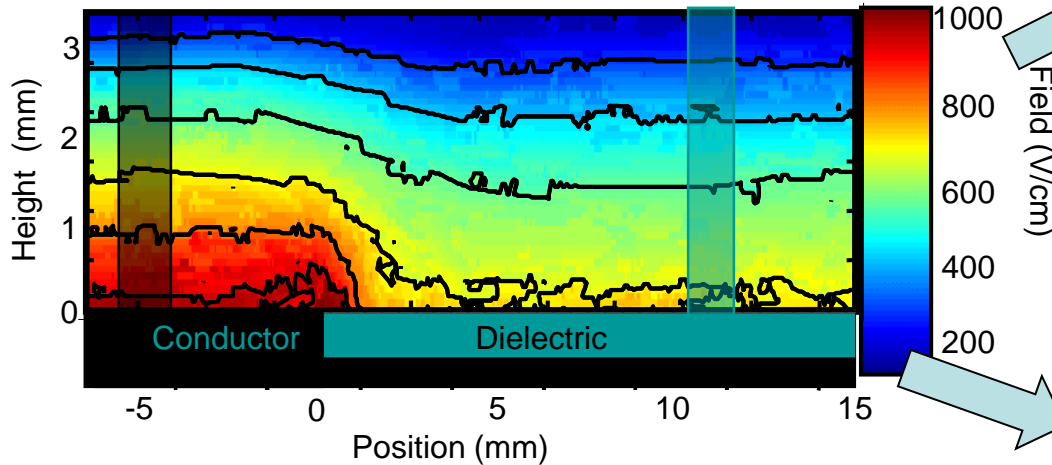
- Firing of lasers synced to rf phase.
 - 13 MHz rf, 20 Hz lasers
 - Time resolved rf voltages
- Gate ICCD after firing of the lasers
 - 2D snapshot of LIF
 - Accumulate for ~ 100's of laser shots
- Repeat as probe laser is incrementally stepped
 - Typically 30 discrete steps
- Post process to determine electric fields
 - Plot LIF vs. wavelength for each pixel
 - Assign electric field, create 2D map



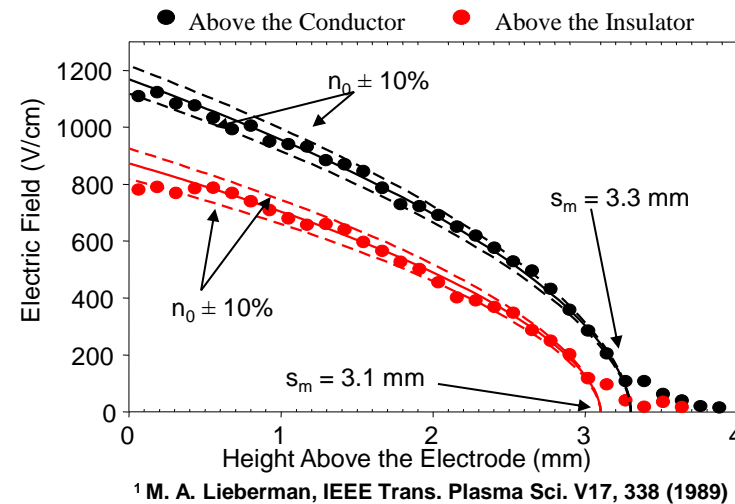
LIF-Dip technique has been used to study boundaries in rf plasma systems

- Representative “toy” problem that looks at “edge effects”
 - Non-uniformities in fields, and energy

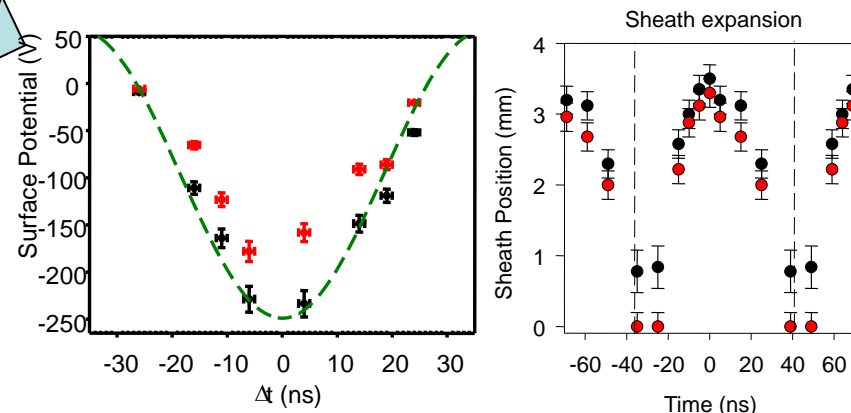
Spatial distribution of electric fields



Spatial structure of the sheath



Temporal evolution of the sheath



This technique is not utilized in arc studies.....

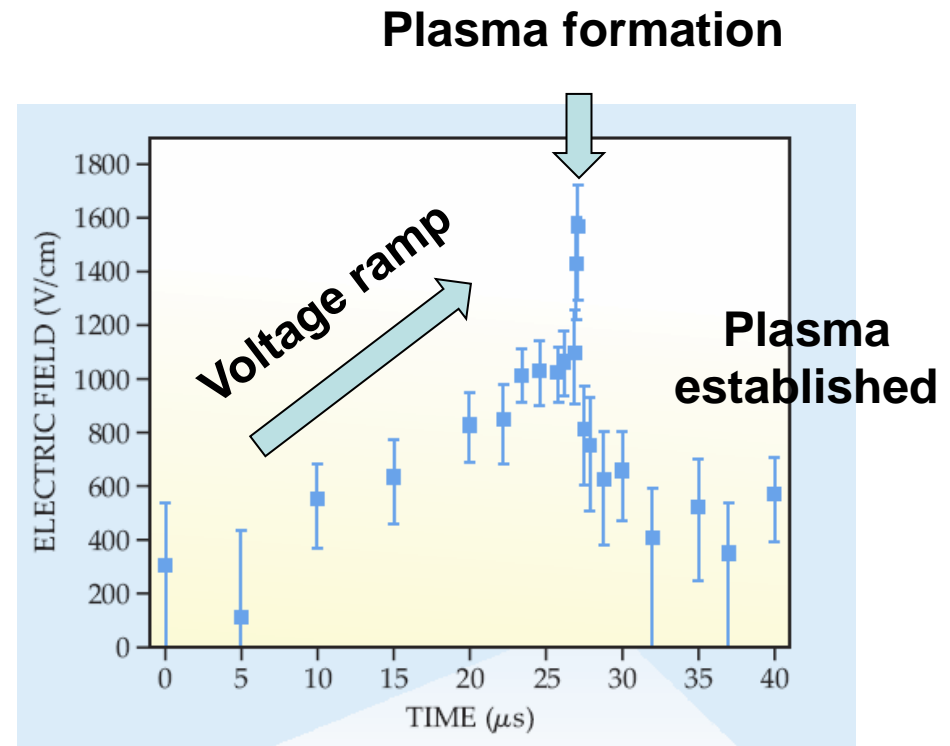
LIF-Dip spectroscopy has been utilized to measure plasma formation between gap

- Eindhoven studies captured the cover of Physics Today (May, 2007)
 - Gerrit Kroesen, Erik Wagenaars and Mark Bowden
- Utilized two-photon absorption from Xe ground state
 - Pre-plasma formation



Physics Today, 60(5) May 2007, page 19

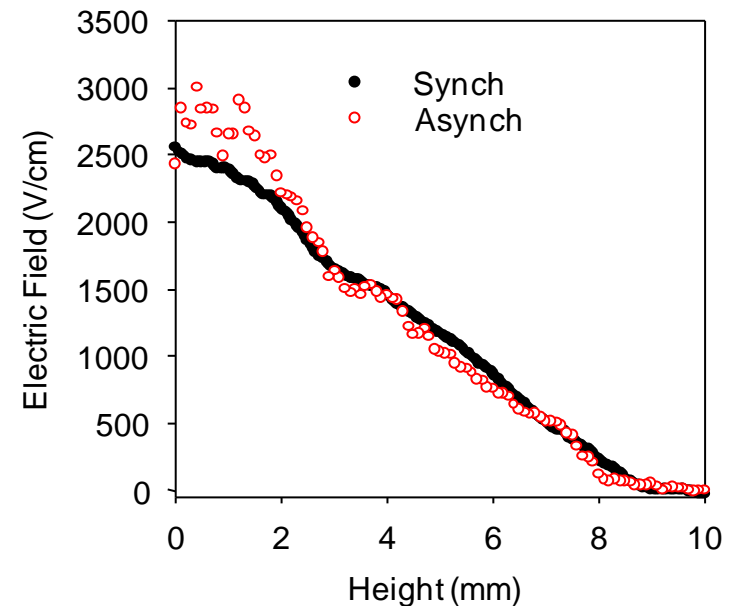
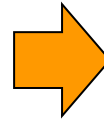
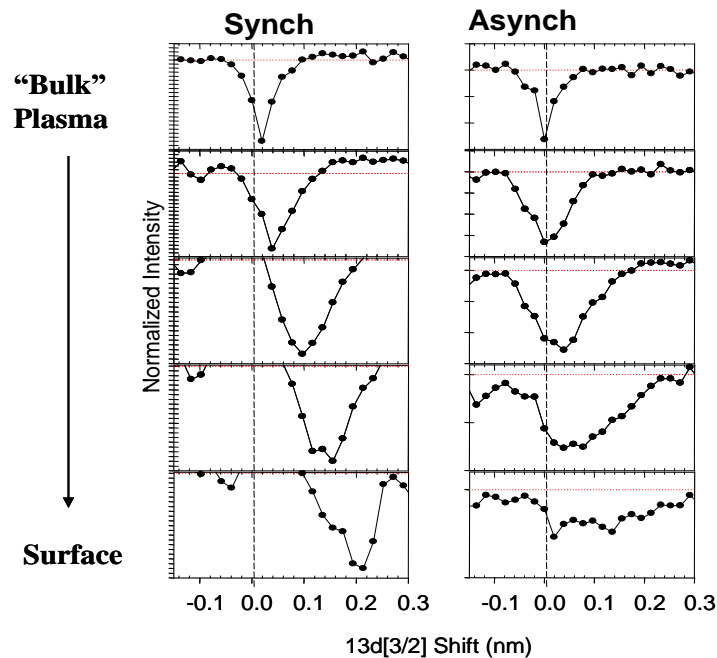
Could this idea be applied to a (vacuum) arc breakdown?



For fast phenomenon, time-resolved (field) measurements becomes challenging

- (at least) Two key challenges need to be overcome
 - Stuff to excite from and resolution of fast phenomena
- Similar to earlier studies on high frequency (>100 MHz) rf plasmas
 - Free run rf, no phase reference
 - Measure total broadened LIF-dip profile

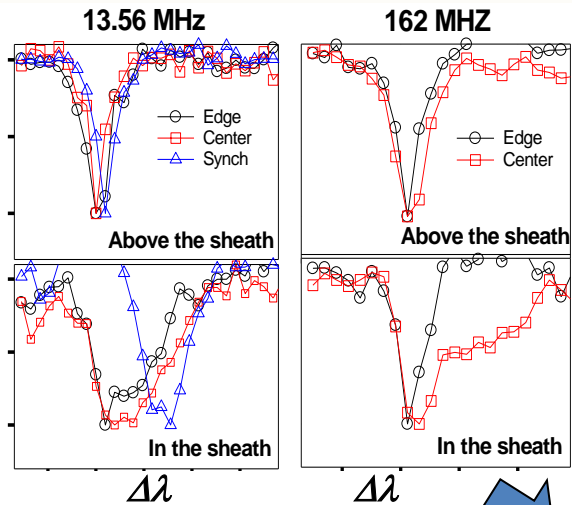
Test technique: 13.56 MHz



There may be ways to side-step limitations to extract useful information

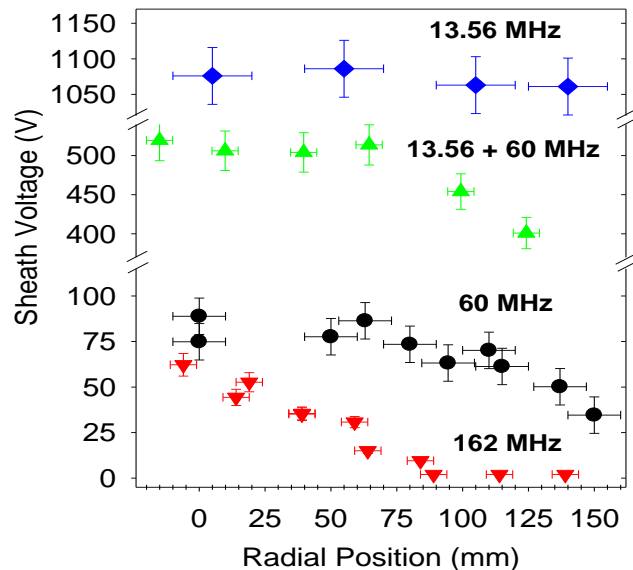
Proof of principle demonstrated in high frequency plasma reactor

LIF-dip profiles

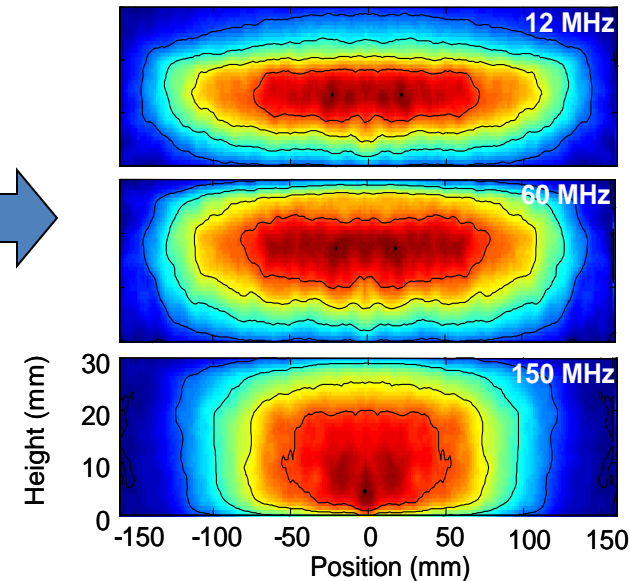


- Apply technique to plasma generated at higher frequencies
 - Measure across wafer, determine peak fields
 - Integrate fields, calculate sheath voltage

Peak sheath voltages



Plasma induced emission



May be able to determine bounds on transient phenomena using approaches like this

Concluding thoughts and future directions

- The arc represents a challenging environment to both experimentalist as well as modelers
 - Spatial scales, temporal scales and gradients all add to these challenges
 - Randomness, stochastic nature of these devices add additional challenge
- “Plasmas or arcs are like children, no two are alike”
 - Clearly application governs ones concerns
 - It is important to look for similarities to gain understanding
- “New” approaches and clever uses of “older” approaches need to be employed to gain access to these phenomena
 - Keep looking for that clever idea that might be useful for addressing some of these questions